CMOS Digital Integrated Circuits Silicon Monolithic

74VHC273FT

1. Functional Description

• Octal D-Type Flip-Flop with Clear

2. General

The 74VHC273FT is an advanced high speed CMOS OCTAL D-TYPE FLIP FLOP fabricated with silicon gate $C^{2}MOS$ technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.

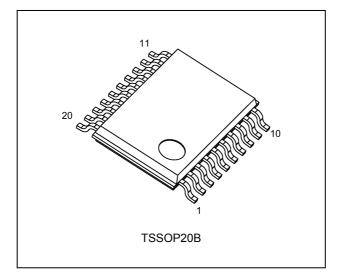
When the $\overline{\text{CLR}}$ input is held "L", the Q outputs are at a low logic level independent of the other inputs.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

3. Features

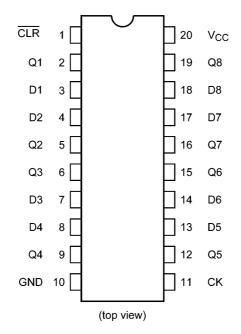
- (1) AEC-Q100 (Rev. H) (Note 1)
- (2) Wide operating temperature range: $T_{opr} = -40$ to 125 °C
- (3) High speed: $f_{MAX} = 165$ MHz (typ.) at $V_{CC} = 5.0$ V
- (4) Low power dissipation: $I_{CC} = 4.0 \ \mu A \ (max)$ at $T_a = 25^{\circ}C$
- (5) High noise immunity: $V_{\text{NIH}} = V_{\text{NIL}} = 28\% V_{\text{CC}}$ (min)
- (6) Power-down protection is provided on all inputs.
- (7) Balanced propagation delays: $t_{PLH} \approx t_{PHL}$
- (8) Wide operating voltage range: $V_{CC(opr)} = 2.0 \text{ V to } 5.5 \text{ V}$
- (9) Low noise: $V_{OLP} = 0.8 V (max)$
- (10) Pin and function compatible with the 74 series (74AC/HC/AHC etc.) 273 type.
- Note1: This device is compliant with the reliability requirements of AEC-Q100. For details, contact your Toshiba sales representative.

4. Packaging

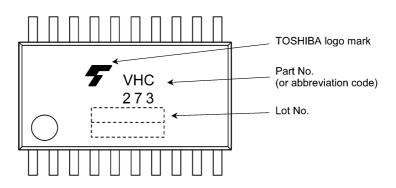


Start of commercial production 2013-05 2017-02-22 Rev.4.0

5. Pin Assignment



6. Marking



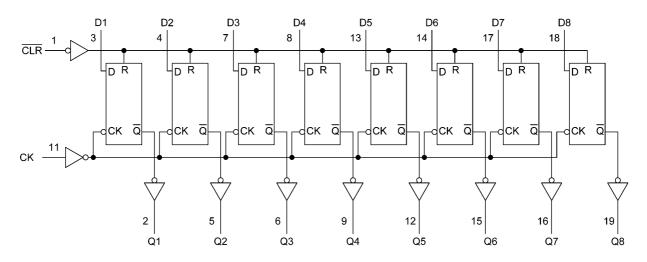
7. IEC Logic Symbol

8. Truth Table

	Inputs		Output	Function
CLR	D	СК	Q	Function
L	Х	Х	L	Clear
н	L		L	—
н	н		Н	—
н	X		Qn	No Change

X: Don't care

9. System Diagram



10. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V _{CC}		-0.5 to 7.0	V
Input voltage	V _{IN}		-0.5 to 7.0	V
Output voltage	V _{OUT}		-0.5 to V _{CC} + 0.5	V
Input diode current	I _{IK}		-20	mA
Output diode current	I _{ОК}		±20	mA
Output current	I _{OUT}		±25	mA
V _{CC} /ground current	I _{CC}		±75	mA
Power dissipation	PD	(Note1)	180	mW
Storage temperature	T _{stg}		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note1: 180 mW in the range of T_a = -40 to 85 °C. From T_a = 85 to 125 °C a derating factor of -3.25 mW/°C shall be applied until 50 mW.

11. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	V _{CC}		2.0 to 5.5	V
Input voltage	V _{IN}		0 to 5.5	V
Output voltage	V _{OUT}		0 to V _{CC}	V
Operating temperature	T _{opr}		-40 to 125	°C
Input rise and fall times	dt/dv	V_{CC} = 3.3 ± 0.3 V	0 to 100	ns/V
		V_{CC} = 5.0 ± 0.5 V	0 to 20	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs and bus inputs must be tied to either V_{CC} or GND.

12. Electrical Characteristics

12.1. DC Characteristics (Unless otherwise specified, $T_a = 25$ °C)

Characteristics	Symbol	Test Condition	I	V _{CC} (V)	Min	Тур.	Max	Unit
High-level input voltage	V _{IH}	—		2.0	1.50	_	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	—	
Low-level input voltage	VIL	—		2.0	—	_	0.50	V
				3.0 to 5.5	—	—	$V_{CC} \times 0.3$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -50 μA	2.0	1.9	2.0	—	V
				3.0	2.9	3.0	—	
				4.5	4.4	4.5	—	
			I _{OH} = -4 mA	3.0	2.58	_	—	
			I _{OH} = -8 mA	4.5	3.94	_	—	
Low-level output voltage	V _{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 50 μA	2.0		0.0	0.1	V
				3.0	—	0.0	0.1	
				4.5	—	0.0	0.1	
			I _{OL} = 4 mA	3.0	—	_	0.36	
			I _{OL} = 8 mA	4.5			0.36	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	_	±0.1	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	_	_	4.0	μA

12.2. DC Characteristics (Unless otherwise specified, $T_a = -40$ to 85 °C)

Characteristics	Symbol	Test Conditior	ı	V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	—		2.0	1.50	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	VIL	—		2.0	_	0.50	V
				3.0 to 5.5	_	$V_{CC} \times 0.3$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			I _{OH} = -4 mA	3.0	2.48	_	
			I _{OH} = -8 mA	4.5	3.80	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 50 μA	2.0	_	0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 4 mA	3.0	_	0.44	
			I _{OL} = 8 mA	4.5	_	0.44	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5		±1.0	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	_	40.0	μA

12.3. DC Characteristics (Unless otherwise specified, $T_a = -40$ to 125 °C)

Characteristics	Symbol	ol Test Condition		V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	—		2.0	1.50	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	VIL	—		2.0	_	0.50	V
				3.0 to 5.5	_	$V_{CC} \times 0.3$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OH} = -50 μA	2.0	1.9	—	V
				3.0	2.9	—	
				4.5	4.4	_	
			I _{OH} = -4 mA	3.0	2.40	—	
			I _{OH} = -8 mA	4.5	3.70	—	
Low-level output voltage	V _{OL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I _{OL} = 50 μA	2.0	_	0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 4 mA	3.0	_	0.55	
			I _{OL} = 8 mA	4.5	_	0.55	
Input leakage current	l _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5		±2.0	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	_	80.0	μA

12.4. Timing Requirements (Unless otherwise specified, $T_a = 25^{\circ}C$, Input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width	$t_{w(L)}, t_{w(H)}$	—	$\textbf{3.3}\pm\textbf{0.3}$	5.5	ns
(CK)			5.0 ± 0.5	5.0	
Minimum pulse width(CLR)	t _{w(L)}	—	$\textbf{3.3}\pm\textbf{0.3}$	5.0	ns
			5.0 ± 0.5	5.0	
Minimum setup time	ts	—	$\textbf{3.3}\pm\textbf{0.3}$	5.5	ns
			5.0 ± 0.5	4.5	
Minimum hold time	t _h	_	$\textbf{3.3}\pm\textbf{0.3}$	1.0	ns
			5.0 ± 0.5	1.0	
Minimum removal time(CLR)	t _{rem}	—	$\textbf{3.3}\pm\textbf{0.3}$	2.5	ns
			5.0 ± 0.5	2.0	

12.5. Timing Requirements (Unless otherwise specified, $T_a = -40$ to 85°C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width	$t_{w(L)}, t_{w(H)}$	—	$\textbf{3.3}\pm\textbf{0.3}$	6.5	ns
(CK)			5.0 ± 0.5	5.0	
Minimum pulse width(CLR)	t _{w(L)}	—	3.3 ± 0.3	6.0	ns
			5.0 ± 0.5	5.0	1
Minimum setup time	ts	—	3.3 ± 0.3	6.5	ns
			5.0 ± 0.5	4.5	1
Minimum hold time	t _h	_	3.3 ± 0.3	1.0	ns
			5.0 ± 0.5	1.0	
Minimum removal time(CLR)	t _{rem}	_	3.3 ± 0.3	2.5	ns
			5.0 ± 0.5	2.0	

12.6. Timing Requirements (Unless otherwise specified, $T_a = -40$ to 125 °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width (CK)	t _{w(L)} ,t _{w(H)}	_	$\textbf{3.3}\pm\textbf{0.3}$	6.5	ns
			5.0 ± 0.5	5.0]
Minimum pulse width (CLR)	t _{w(L)}	_	3.3 ± 0.3	6.0	ns
			5.0 ± 0.5	5.0	
Minimum setup time	ts	_	$\textbf{3.3}\pm\textbf{0.3}$	6.5	ns
			5.0 ± 0.5	4.5	1
Minimum hold time	t _h	_	$\textbf{3.3}\pm\textbf{0.3}$	1.0	ns
			5.0 ± 0.5	1.0	1
Minimum removal time (CLR)	t _{rem}	_	$\textbf{3.3}\pm\textbf{0.3}$	2.5	ns
			5.0 ± 0.5	2.0	

12.7. AC Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	—	8.7	13.6	ns
(CK-Q)					50	_	11.2	17.1	
				5.0 ± 0.5	15	_	5.8	9.0	
					50	_	7.3	11.0	
Propagation delay time	t _{PHL}		—	3.3 ± 0.3	15	_	8.9	13.6	ns
(CLR-Q)					50	_	11.4	17.1	
				5.0 ± 0.5	15	_	5.2	8.5	
					50	_	6.7	10.5	
Maximum clock frequency	f _{MAX}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	75	120		MHz
					50	50	75	_	
				5.0 ± 0.5	15	120	165	_	
					50	80	110		
Output skew	t _{osLH} ,t _{osHL}	(Note 1)	_	3.3 ± 0.3	50	_	_	1.5	ns
				5.0 ± 0.5	50	_	_	1.0	
Input capacitance	C _{IN}		_			_	4	10	pF
Power dissipation capacitance	C _{PD}	(Note 2)	_			_	31	_	pF

Note 1: Parameter guaranteed by design. $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

 $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$ (per bit)

And the total C_{PD} when n pcs. of latch operate can be gained by the following equation.

 C_{PD} (total) = 22 + 9 × n

12.8. AC Characteristics

(Unless otherwise specified, $T_a = -40$ to 85 °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	1.0	16.0	ns
(CK-Q)					50	1.0	19.5	
				5.0 ± 0.5	15	1.0	10.5	
					50	1.0	12.5	
Propagation delay time	t _{PHL}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	1.0	16.0	ns
(CLR-Q)					50	1.0	19.5	
				5.0 ± 0.5	15	1.0	10.0	
					50	1.0	12.0	
Maximum clock frequency	f _{MAX}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	65	—	MHz
					50	45	—	
				5.0 ± 0.5	15	100	_	
					50	70	_	
Output skew	t _{osLH} ,t _{osHL}	(Note 1)	_	$\textbf{3.3}\pm\textbf{0.3}$	50	_	1.5	ns
				5.0 ± 0.5	50	_	1.0	
Input capacitance	C _{IN}					_	10	pF

Note 1: Parameter guaranteed by design. $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$

12.9. AC Characteristics (Unless otherwise specified, T_a = -40 to 125 °C, Input: t_r = t_f = 3 ns)

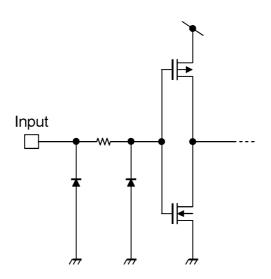
Characteristics	Symbol	Note	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}		—	$\textbf{3.3}\pm\textbf{0.3}$	15	1.0	18.0	ns
(CK-Q)					50	1.0	21.5	
				5.0 ± 0.5	15	1.0	12.0	
					50	1.0	14.0	
Propagation delay time (CLR-Q)	t _{PHL}		_	$\textbf{3.3}\pm\textbf{0.3}$	15	1.0	18.0	ns
					50	1.0	21.5	
				5.0 ± 0.5	15	1.0	11.5	
					50	1.0	13.5	
Maximum clock frequency	f _{MAX}		_	$\textbf{3.3}\pm\textbf{0.3}$	15	60	_	MHz
					50	40	_	
				5.0 ± 0.5	15	95	_	
					50	60	_	
Output skew	t _{osLH} ,t _{osHL}	(Note 1)	_	$\textbf{3.3}\pm\textbf{0.3}$	50	_	1.5	ns
				5.0 ± 0.5	50	_	1.0	
Input capacitance	C _{IN}					_	10	pF

Note 1: Parameter guaranteed by design. $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$

12.10. Noise Characteristics (Unless otherwise specified, $T_a = 25^{\circ}$ C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	C _L = 50 pF	5.0	0.5	0.8	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	C _L = 50 pF	5.0	-0.5	-0.8	
Minimum high-level dynamic input voltage	V _{IHD}	C _L = 50 pF	5.0	_	3.5	
Maximum low-level dynamic input voltage	V _{ILD}	C _L = 50 pF	5.0	_	1.5	

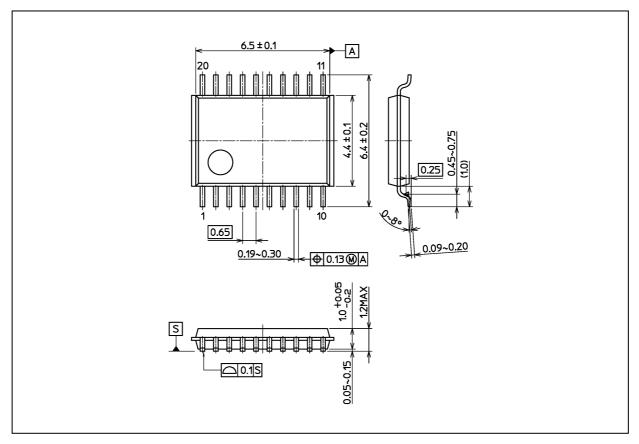
13. Input Equivalent Circuit





Package Dimensions

Unit: mm



Weight: 0.071 g (typ.)

	Package Name(s)	
Nickname: TSSOP20B		

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